Searcn Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/723,840	WEN ET AL.	
Examiner	Art Unit	
Tan Ho	2821	

SEARCHED			
Class	Subclass	Date	Examiner
343	702	12/8/05	7.4.
	700MS		
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARCH		
	DATE	EXMR
West	12/11/05	-T.H.